OPA141
OPA2141
OPA4141

单电源、10MHz、轨至轨输出 、低噪声、 JFET 放大器

查询样品: OPA141, OPA2141, OPA4141

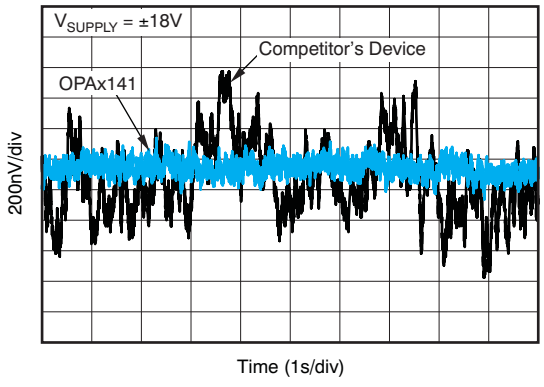
特性

- 低电源电流：**2.3mA**（最大值）
- 低失调漂移：**10μV/**℃（最大值）
- 低输入偏置电流：**20pA**（最大值）
- 超低**1/f**噪声：**250nV$_{PP}$**
- 低噪声：**6.5nV/**$\sqrt{Hz}$
- 宽带宽：**10MHz**
- 转换速率：**20 V/μs**
- 输入电压范围包括**V—**
- 轨至轨输出
- 单电源操作：**4.5V**至**36**
- 双电源操作：**±2.25V**至**±18V**
- 无相位反转
- **MSOP-8**、**TSSOP** 封装

应用

- 电池供电型仪器
- 工业控制
- 医疗仪表
- 光电二极管放大器
- 有源滤波器
- 数据采集系统
- 便携式音频
- 自动测试系统

图 **1. 0.1Hz**至**10Hz**噪声



说明

OPA141、OPA2141 和 OPA4141放大器系列为低功耗 JFET输入放大器，具有优良的漂移特性和低输入偏置电流。 轨至轨输出摆幅与包括了V—的输入范围使得设计人员不仅能够充分利用 JFET 放大器的低噪声特性，同时还能实现与新式的单电源、高精度模数转换器 (ADC) 和数模转换器 (DAC) 的连接。

OPA141 实现了10MHz 的单位增益带宽和 20 V/μs 的转换速率，而仅消耗 1.8mA（典型值）的静态电流。该器件采用 4.5V 至 36V 的单工作电源或±2.25V 至±18V 的双工作电源。

所有版本的技术规格均针对－40℃ 至＋125℃ 的温度范围而拟订，以便在最严苛的环境中使用。
OPA141（单通道器件）和 OPA2141（双通道器件）版本采用MSOP-8 和 SO-8 封装；OPA4141（四通道器件）则采用 SO-14 和 TSSOP-14 封装。

相关产品

特性	产品
高精度、低功耗、10MHz FET输入工业运算放大器	OPA140(1)
采用SOT-23封装的2.2nV/$\sqrt{Hz}$、低功耗、36V运算放大器	OPA209(1)
低噪声、高精度、JFET 输入运算放大器	OPA827
低噪声、低I_Q、高精度运算放大器	OPA376
高速、FET 输入运算放大器	OPA132

1. 前瞻性产品，预计于2010年第三季度供货。

This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

ABSOLUTE MAXIMUM RATINGS(1)

Over operating free-air temperature range (unless otherwise noted).

		VALUE	UNIT
Supply Voltage		±20	V
Signal Input Terminals	Voltage(2)	(V–) –0.5 to (V+) +0.5	V
	Current(2)	±10	mA
Output Short-Circuit(3)		Continuous	
Operating Temperature, T_A		–55 to +150	°C
Storage Temperature, T_A		–65 to +150	°C
Junction Temperature, T_J		+150	°C
ESD Ratings	Human Body Model (HBM)	2000	V
	Charged Device Model (CDM)	500	V

(1) Stresses above these ratings may cause permanent damage. Exposure to absolute maximum conditions for extended periods may degrade device reliability. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those specified is not supported.
(2) Input terminals are diode-clamped to the power-supply rails. Input signals that can swing more than 0.5V beyond the supply rails should be current limited to 10 mA or less.
(3) Short-circuit to $V_S/2$ (ground in symmetrical dual-supply setups), one amplifier per package.

PACKAGE INFORMATION(1)

PRODUCT	PACKAGE-LEAD	PACKAGE DESIGNATOR	PACKAGE MARKING
OPA141	SO-8	D	O141A
	MSOP-8	DGK	141
OPA2141	SO-8	D	O2141A
	MSOP-8	DGK	2141
OPA4141	TSSOP-14	PW	O4141A
	SO-14	D	O4141AG4

(1) For the most current package and ordering information see the Package Option Addendum at the end of this document, or visit the device product folder at www.ti.com.

THERMAL INFORMATION

THERMAL METRIC		OPA141, OPA2141	OPA141, OPA2141	UNITS
		D (SO)	DGK (MSOP)(1)	
		8	8	
θ_{JA}	Junction-to-ambient thermal resistance(2)	160	180	°C/W
$\theta_{JC(top)}$	Junction-to-case(top) thermal resistance(3)	75	55	
θ_{JB}	Junction-to-board thermal resistance(4)	60	130	
ψ_{JT}	Junction-to-top characterization parameter(5)	9	n/a	
ψ_{JB}	Junction-to-board characterization parameter(6)	50	120	
$\theta_{JC(bottom)}$	Junction-to-case(bottom) thermal resistance(7)	n/a	n/a	

(1) For more information about traditional and new thermal metrics, see the *IC Package Thermal Metrics* application report, SPRA953.
(2) The junction-to-ambient thermal resistance under natural convection is obtained in a simulation on a JEDEC-standard, high-K board, as specified in JESD51-7, in an environment described in JESD51-2a.
(3) The junction-to-case (top) thermal resistance is obtained by simulating a cold plate test on the package top. No specific JEDEC-standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.
(4) The junction-to-board thermal resistance is obtained by simulating in an environment with a ring cold plate fixture to control the PCB temperature, as described in JESD51-8.
(5) The junction-to-top characterization parameter, ψ_{JT}, estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ_{JA}, using a procedure described in JESD51-2a (sections 6 and 7).
(6) The junction-to-board characterization parameter, ψ_{JB}, estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ_{JA} , using a procedure described in JESD51-2a (sections 6 and 7).
(7) The junction-to-case (bottom) thermal resistance is obtained by simulating a cold plate test on the exposed (power) pad. No specific JEDEC standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.

THERMAL INFORMATION

THERMAL METRIC		OPA4141	OPA4141	UNITS
		D (SO)	PW (TSSOP)(1)	
		14	14	
θ_{JA}	Junction-to-ambient thermal resistance(2)	97	135	°C/W
$\theta_{JC(top)}$	Junction-to-case(top) thermal resistance(3)	56	45	
θ_{JB}	Junction-to-board thermal resistance(4)	53	66	
ψ_{JT}	Junction-to-top characterization parameter(5)	19	n/a	
ψ_{JB}	Junction-to-board characterization parameter(6)	46	60	
$\theta_{JC(bottom)}$	Junction-to-case(bottom) thermal resistance(7)	n/a	n/a	

(1) For more information about traditional and new thermal metrics, see the *IC Package Thermal Metrics* application report, SPRA953.
(2) The junction-to-ambient thermal resistance under natural convection is obtained in a simulation on a JEDEC-standard, high-K board, as specified in JESD51-7, in an environment described in JESD51-2a.
(3) The junction-to-case (top) thermal resistance is obtained by simulating a cold plate test on the package top. No specific JEDEC-standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.
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(6) The junction-to-board characterization parameter, ψ_{JB}, estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ_{JA} , using a procedure described in JESD51-2a (sections 6 and 7).
(7) The junction-to-case (bottom) thermal resistance is obtained by simulating a cold plate test on the exposed (power) pad. No specific JEDEC standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.

ELECTRICAL CHARACTERISTICS: V_S = +4.5V to +36V; ±2.25V to ±18V

Boldface limits apply over the specified temperature range, **T_A = –40°C to +125°C**.
At T_A = +25°C, R_L = 2kΩ connected to midsupply, V_{CM} = V_{OUT} = midsupply, unless otherwise noted.

PARAMETER		CONDITIONS	OPA141, OPA2141, OPA4141			UNIT
			MIN	TYP	MAX	
OFFSET VOLTAGE						
Offset Voltage, RTI	V_{OS}	V_S = ±18V		±1	±3.5	mV
Over Temperature		**V_S = ±18V**			**±4.3**	**mV**
Drift	**dV_{OS}/dT**	**V_S = ±18V**		**±2**	**±10**	**µV/°C**
vs Power Supply	PSRR	V_S = ±2.25V to ±18V		±0.14	±2	µV/V
Over Temperature		**V_S = ±2.25V to ±18V**			**±4**	**µV/V**
INPUT BIAS CURRENT						
Input Bias Current	I_B			±2	±20	pA
Over Temperature					**±5**	**nA**
Input Offset Current	I_{OS}			±2	±20	pA
Over Temperature					**±1**	**nA**
NOISE						
Input Voltage Noise						
f = 0.1Hz to 10Hz				250		nV_{PP}
f = 0.1Hz to 10Hz				42		nV_{RMS}
Input Voltage Noise Density	e_n					
f = 10Hz				12		$nV/\sqrt{Hz}$
f = 100Hz				6.5		$nV/\sqrt{Hz}$
f = 1kHz				6.5		$nV/\sqrt{Hz}$
Input Current Noise Density	i_n					
f = 1kHz				0.8		$fA/\sqrt{Hz}$
INPUT VOLTAGE RANGE						
Common-Mode Voltage Range	**V_{CM}**		**(V–) –0.1**		**(V+)–3.5**	**V**
Common-Mode Rejection Ratio	CMRR	V_S = ±18V, V_{CM} = (V–) –0.1V to (V+) – 3.5V	120	126		dB
Over Temperature		**V_S = ±18V, V_{CM} = (V–) –0.1V to (V+) – 3.5V**	**120**			**dB**
INPUT IMPEDANCE						
Differential				10^{13} || 8		Ω || pF
Common-Mode		V_{CM} = (V–) –0.1V to (V+) –3.5V		10^{13} || 6		Ω || pF
OPEN-LOOP GAIN						
Open-Loop Voltage Gain	A_{OL}	V_O = (V–)+0.35V to (V+)–0.35V, R_L = 2kΩ	114	126		dB
Over Temperature		**V_O = (V–)+0.35V to (V+)–0.35V, R_L = 2kΩ**	**108**			**dB**
FREQUENCY RESPONSE						
Gain Bandwidth Product	BW			10		MHz
Slew Rate				20		V/µs
Settling Time, 12-bit (0.024)				880		ns
THD+N		1kHz, G = 1, V_O = $3.5V_{RMS}$		0.00005		%
Overload Recovery Time				600		ns

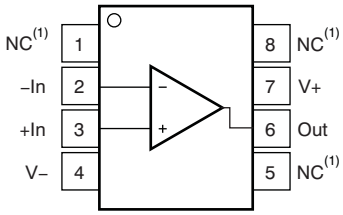
ELECTRICAL CHARACTERISTICS: V_S = +4.5V to +36V; ±2.25V to ±18V (continued)

Boldface limits apply over the specified temperature range, **T_A = –40°C to +125°C**.
At T_A = +25°C, R_L = 2kΩ connected to midsupply, V_{CM} = V_{OUT} = midsupply, unless otherwise noted.

PARAMETER		CONDITIONS	OPA141, OPA2141, OPA4141			UNIT
			MIN	TYP	MAX	
OUTPUT						
Voltage Output	**V_O**	**R_L = 10kΩ**	**(V–)+0.2**		**(V+)–0.2**	**V**
		R_L = 2kΩ	**(V–)+0.35**		**(V+)–0.35**	**V**
Short-Circuit Current	I_{SC}	Source		+36		mA
		Sink		–30		mA
Capacitive Load Drive	C_{LOAD}		See Figure 20 and Figure 21			
Open-Loop Output Impedance	R_O	f = 1MHz, I_O = 0 (See Figure 19)		10		Ω
POWER SUPPLY						
Specified Voltage Range	V_S		±2.25		±18	V
Quiescent Current (per amplifier)	I_Q	I_O = 0mA		1.8	2.3	mA
Over Temperature					**3.1**	**mA**
CHANNEL SEPARATION						
Channel Separation		At dc		0.02		µV/V
		At 100kHz		10		µV/V
TEMPERATURE RANGE						
Specified Range			–40		+125	°C
Operating Range			–55		+150	°C

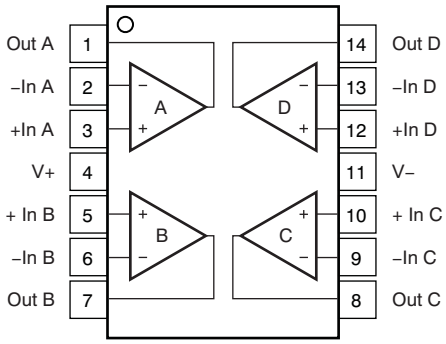
PIN ASSIGNMENTS

OPA141
SO-8, MSOP-8
(TOP VIEW)

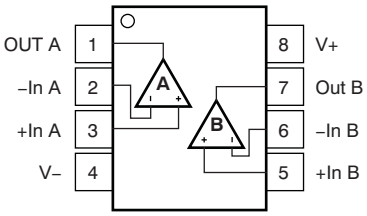


(1) NC denotes no internal connection.

OPA4141
SO-14, TSSOP-14
(TOP VIEW)



OPA2141
SO-8, MSOP-8
(TOP VIEW)



SIMPLIFIED BLOCK DIAGRAM

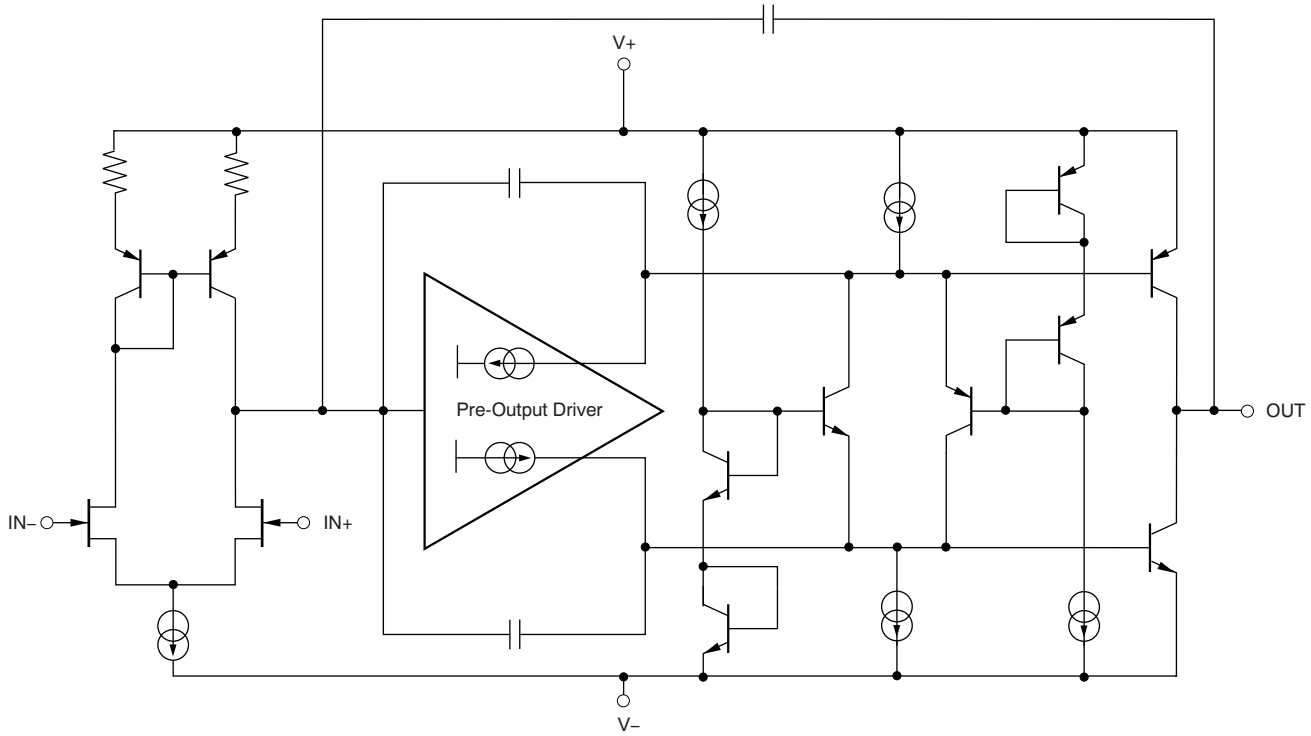


Figure 2.

TYPICAL CHARACTERISTICS SUMMARY

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TYPICAL CHARACTERISTICS

At T_A = +25°C, V_S = ±18V, R_L = 2kΩ connected to midsupply, V_{CM} = V_{OUT} = midsupply, unless otherwise noted.

OFFSET VOLTAGE PRODUCTION DISTRIBUTION

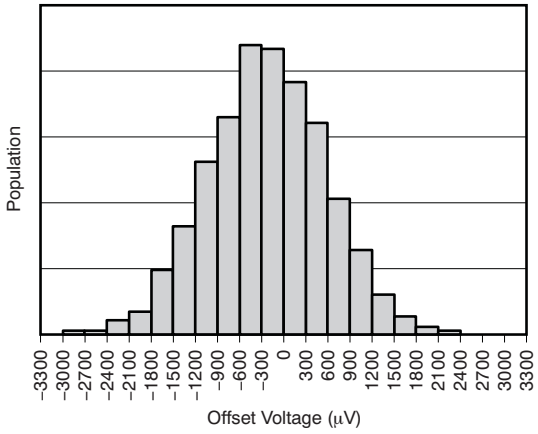


Figure 3.

OFFSET VOLTAGE DRIFT DISTRIBUTION

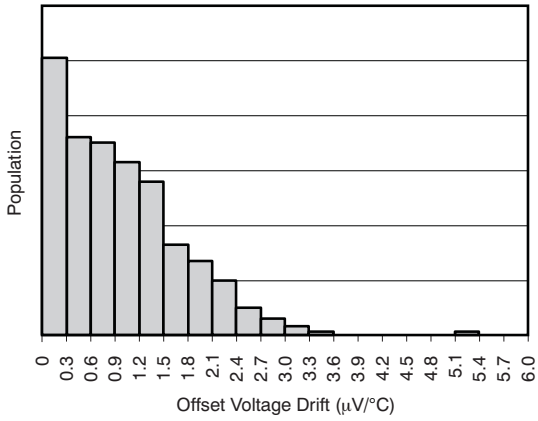


Figure 4.

OFFSET VOLTAGE vs COMMON-MODE VOLTAGE

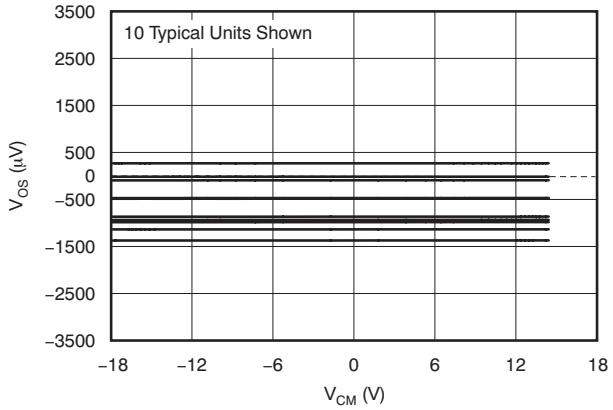


Figure 5.

I_B AND I_{OS} vs COMMON-MODE VOLTAGE

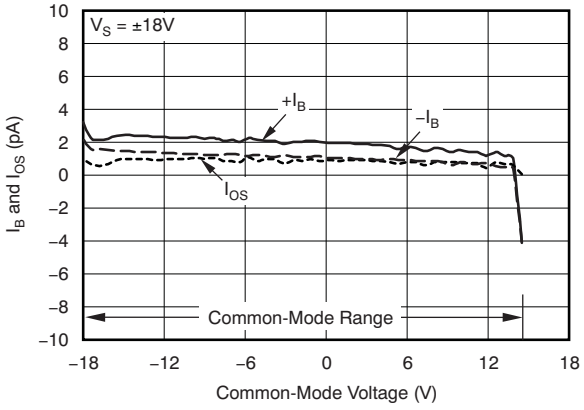


Figure 6.

OUTPUT VOLTAGE SWING vs OUTPUT CURRENT (MAX SUPPLY)

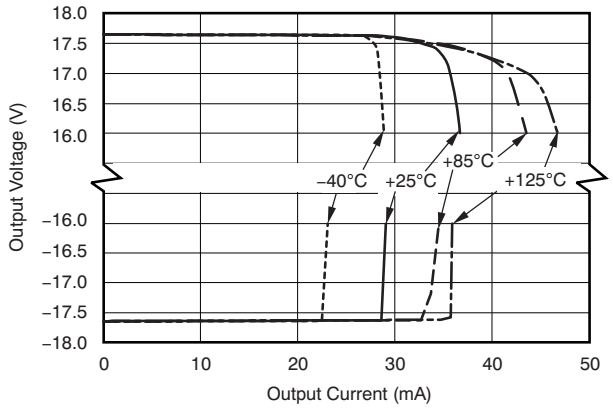


Figure 7.

CMRR AND PSRR vs FREQUENCY (Referred to Input)

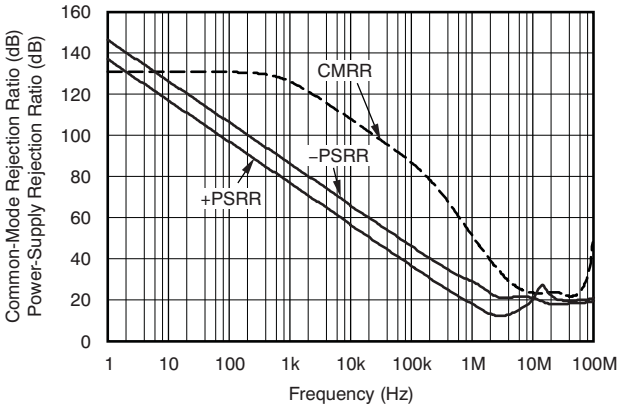


Figure 8.

TYPICAL CHARACTERISTICS (continued)

At T_A = +25°C, V_S = ±18V, R_L = 2kΩ connected to midsupply, V_{CM} = V_{OUT} = midsupply, unless otherwise noted.

COMMON-MODE REJECTION RATIO vs TEMPERATURE

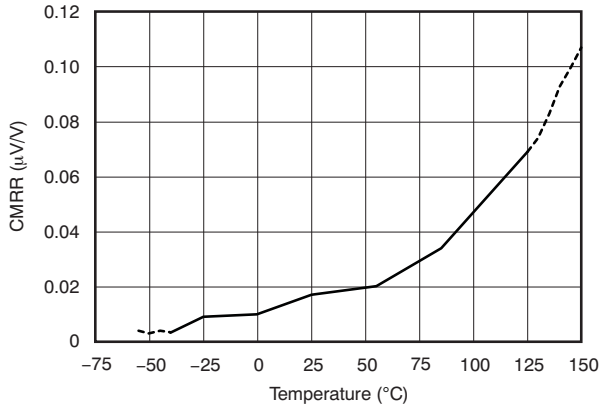


Figure 9.

0.1Hz to 10Hz NOISE

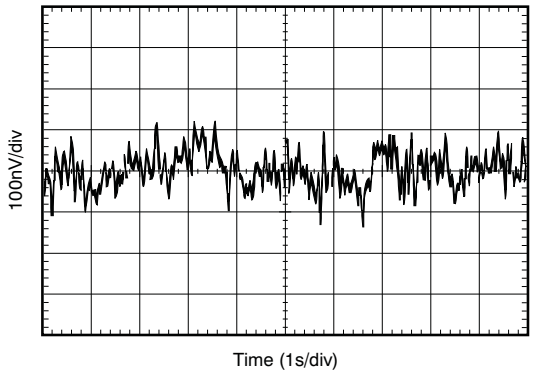


Figure 10.

INPUT VOLTAGE NOISE DENSITY vs FREQUENCY

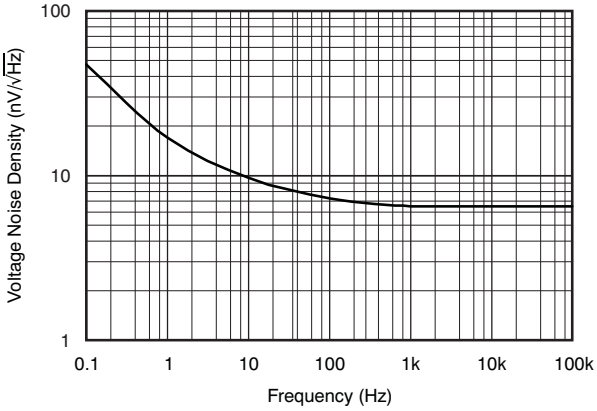


Figure 11.

THD+N RATIO vs FREQUENCY

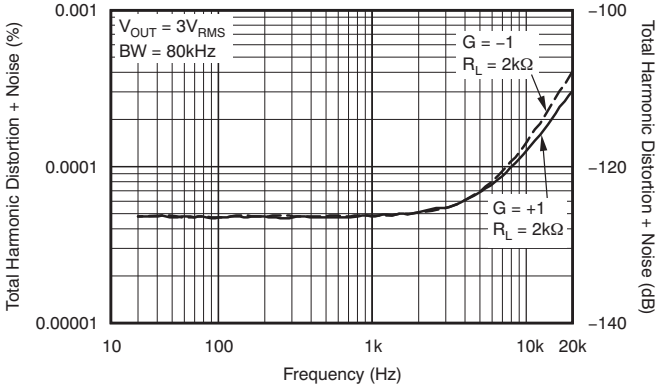


Figure 12.

THD+N RATIO vs OUTPUT AMPLITUDE

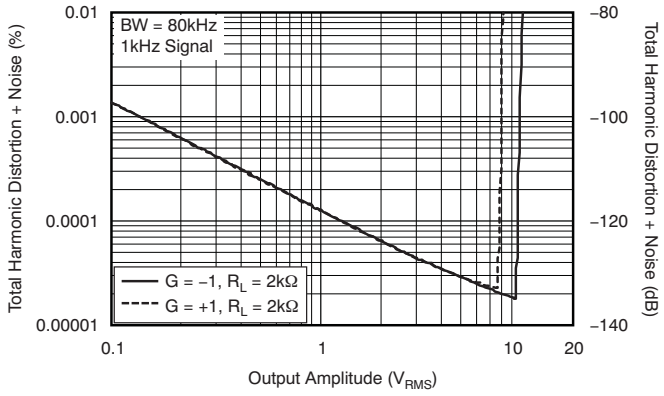


Figure 13.

QUIESCENT CURRENT vs TEMPERATURE

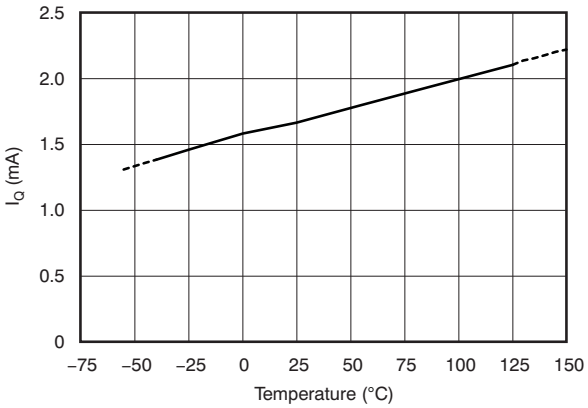


Figure 14.

TYPICAL CHARACTERISTICS (continued)

At T_A = +25°C, V_S = ±18V, R_L = 2kΩ connected to midsupply, V_{CM} = V_{OUT} = midsupply, unless otherwise noted.

QUIESCENT CURRENT vs SUPPLY VOLTAGE

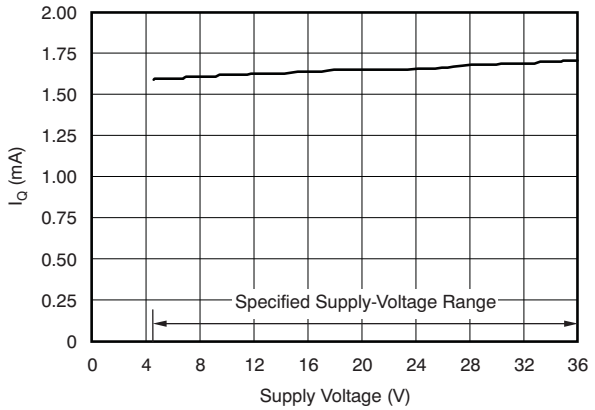


Figure 15.

GAIN AND PHASE vs FREQUENCY

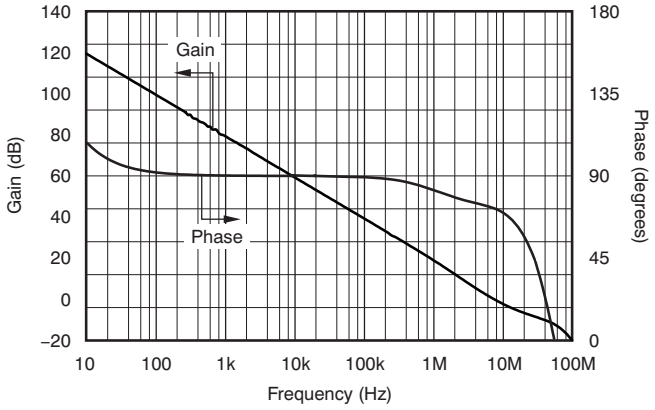


Figure 16.

CLOSED-LOOP GAIN vs FREQUENCY

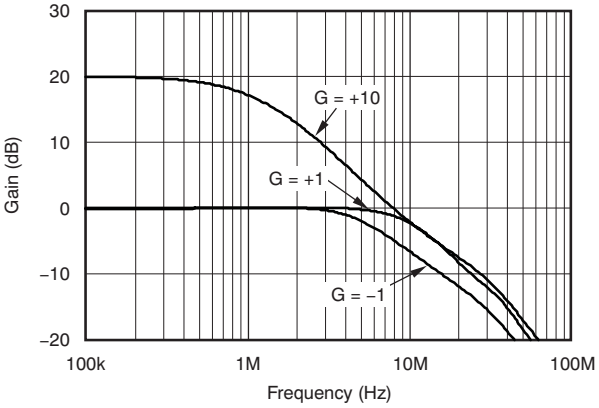


Figure 17.

OPEN-LOOP GAIN vs TEMPERATURE

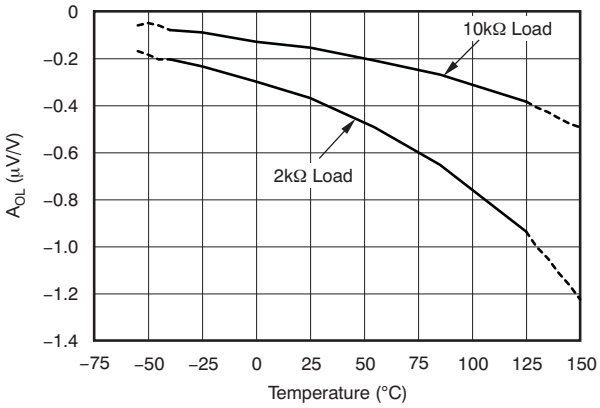


Figure 18.

OPEN-LOOP OUTPUT IMPEDANCE vs FREQUENCY

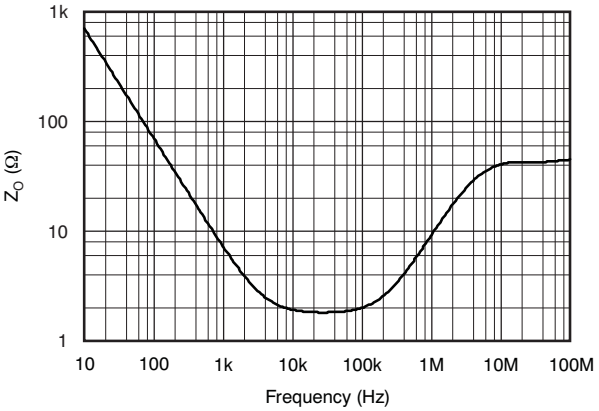


Figure 19.

SMALL-SIGNAL OVERSHOOT vs CAPACITIVE LOAD (100mV Output Step)

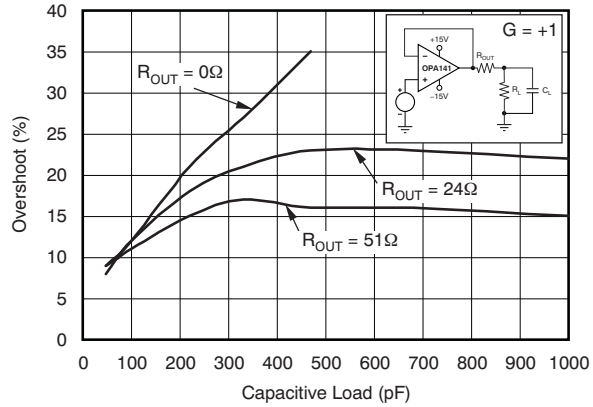


Figure 20.

TYPICAL CHARACTERISTICS (continued)

At T_A = +25°C, V_S = ±18V, R_L = 2kΩ connected to midsupply, V_{CM} = V_{OUT} = midsupply, unless otherwise noted.

SMALL-SIGNAL OVERSHOOT vs CAPACITIVE LOAD (100mV Output Step)

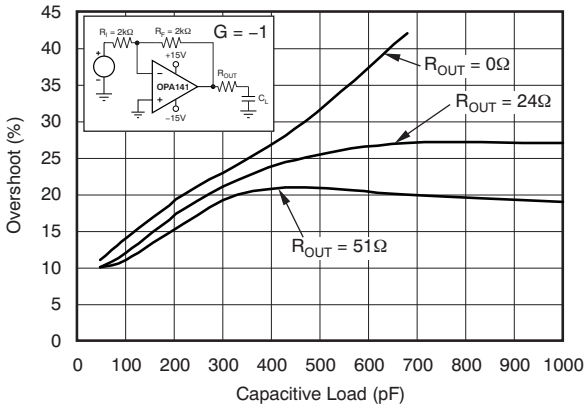


Figure 21.

NO PHASE REVERSAL

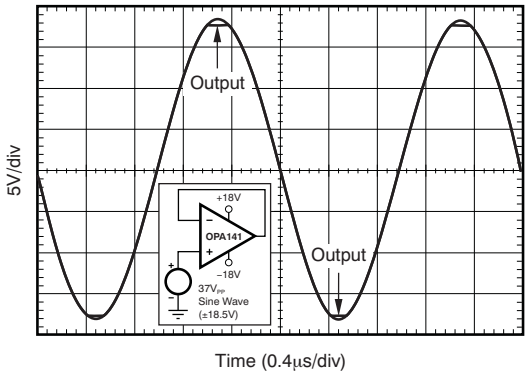


Figure 22.

POSITIVE OVERLOAD RECOVERY

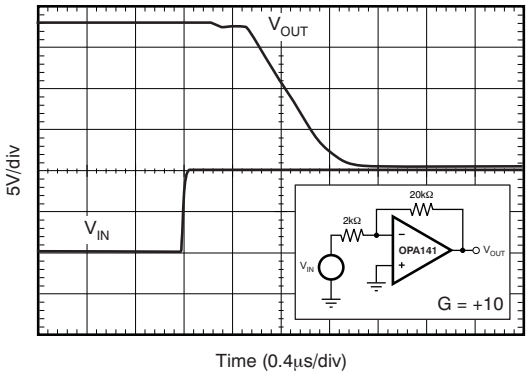


Figure 23.

NEGATIVE OVERLOAD RECOVERY

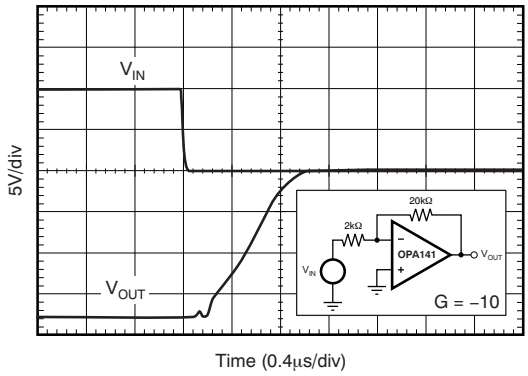


Figure 24.

SMALL-SIGNAL STEP RESPONSE (100mV)

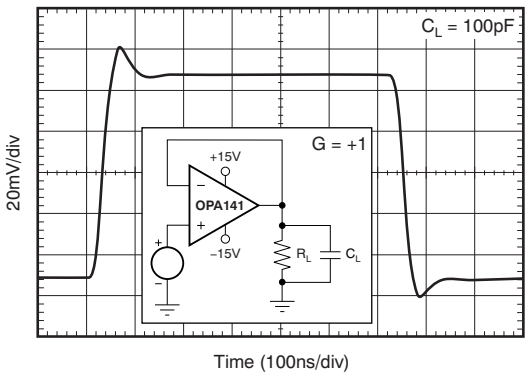


Figure 25.

SMALL-SIGNAL STEP RESPONSE (100mV)

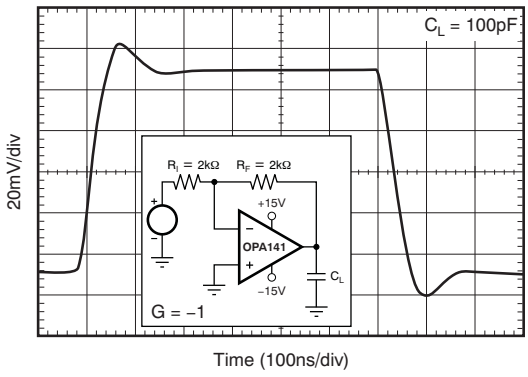


Figure 26.

TYPICAL CHARACTERISTICS (continued)

At T_A = +25°C, V_S = ±18V, R_L = 2kΩ connected to midsupply, V_{CM} = V_{OUT} = midsupply, unless otherwise noted.

LARGE-SIGNAL STEP RESPONSE

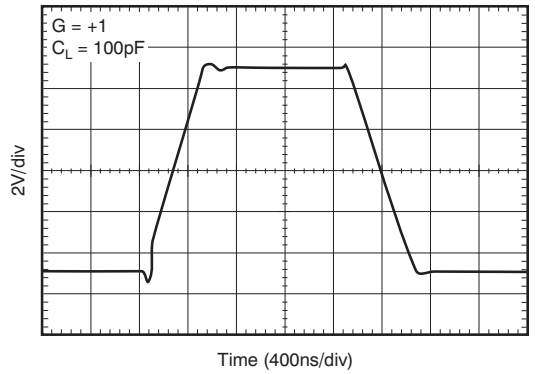


Figure 27.

LARGE-SIGNAL STEP RESPONSE

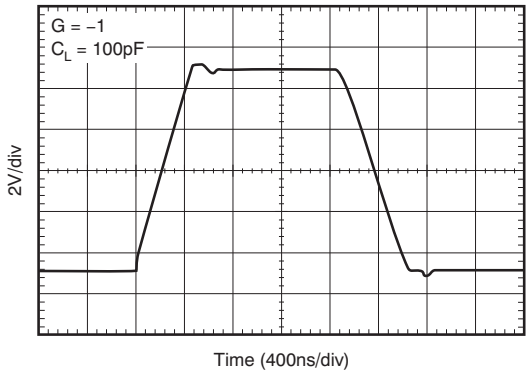


Figure 28.

SHORT-CIRCUIT CURRENT vs TEMPERATURE

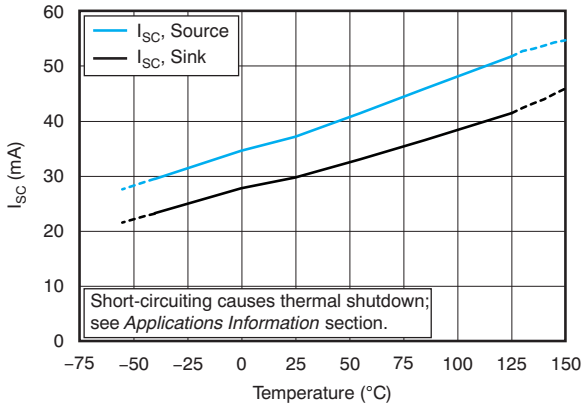


Figure 29.

MAXIMUM OUTPUT VOLTAGE vs FREQUENCY

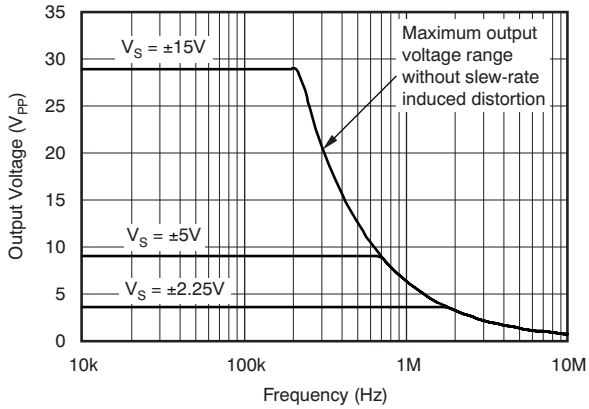


Figure 30.

CHANNEL SEPARATION vs FREQUENCY

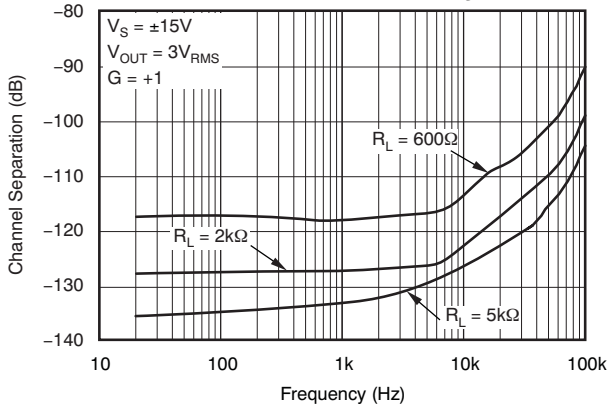


Figure 31.

APPLICATION INFORMATION

The OPA141, OPA2141, and OPA4141 are unity-gain stable, operational amplifiers with very low noise, input bias current, and input offset voltage. Applications with noisy or high-impedance power supplies require decoupling capacitors placed close to the device pins. In most cases, 0.1µF capacitors are adequate. Figure 2 shows a simplified schematic of the OPA141.

OPERATING VOLTAGE

The OPA141, OPA2141, and OPA4141 series of op amps can be used with single or dual supplies from an operating range of V_S = +4.5V (±2.25V) and up to V_S = +36V (±18V). These devices do not require symmetrical supplies; they only require a minimum supply voltage of +4.5V (±2.25V). For V_S less than ±3.5V, the common-mode input range does not include midsupply. Supply voltages higher than +40V can permanently damage the device; see the Absolute Maximum Ratings table. Key parameters are specified over the operating temperature range, T_A = –40°C to +125°C. Key parameters that vary over the supply voltage or temperature range are shown in the Typical Characteristics section of this data sheet.

CAPACITIVE LOAD AND STABILITY

The dynamic characteristics of the OPAx141 have been optimized for commonly encountered gains, loads, and operating conditions. The combination of low closed-loop gain and high capacitive loads decreases the phase margin of the amplifier and can lead to gain peaking or oscillations. As a result, heavier capacitive loads must be isolated from the output. The simplest way to achieve this isolation is to add a small resistor (R_{OUT} equal to 50Ω, for example) in series with the output.

Figure 20 and Figure 21 illustrate graphs of *Small-Signal Overshoot vs Capacitive Load* for several values of R_{OUT}. Also, refer to Applications Bulletin AB-028 (literature number SBOA015, available for download from the TI web site) for details of analysis techniques and application circuits.

NOISE PERFORMANCE

Figure 32 shows the total circuit noise for varying source impedances with the operational amplifier in a unity-gain configuration (with no feedback resistor network and therefore no additional noise contributions). The OPA141 and OPA211 are shown with total circuit noise calculated. The op amp itself contributes both a voltage noise component and a current noise component. The voltage noise is commonly modeled as a time-varying component of the offset voltage. The current noise is modeled as the time-varying component of the input bias current and reacts with the source resistance to create a voltage component of noise. Therefore, the lowest noise op amp for a given application depends on the source impedance. For low source impedance, current noise is negligible, and voltage noise generally dominates. The OPA141, OPA2141, and OPA4141 family has both low voltage noise and extremely low current noise because of the FET input of the op amp. As a result, the current noise contribution of the OPAx141 series is negligible for any practical source impedance, which makes it the better choice for applications with high source impedance.

The equation in Figure 32 shows the calculation of the total circuit noise, with these parameters:

- e_n = voltage noise
- I_n = current noise
- R_S = source impedance
- k = Boltzmann's constant = 1.38 × 10^{-23} J/K
- T = temperature in degrees Kelvin (K)

For more details on calculating noise, see the section on Basic Noise Calculations.

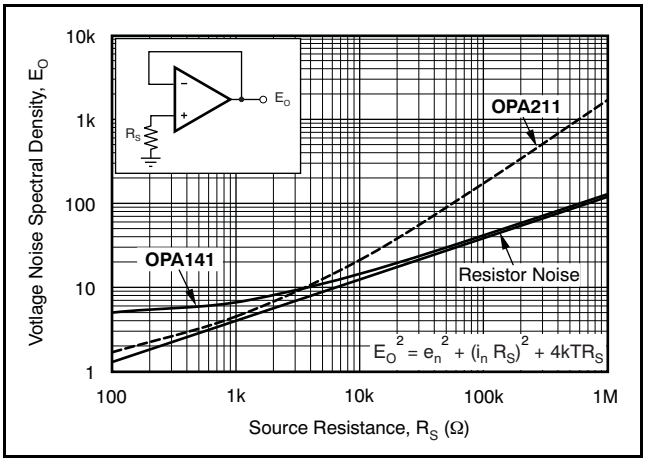


Figure 32. Noise Performance of the OPA141 and OPA211 in Unity-Gain Buffer Configuration

BASIC NOISE CALCULATIONS

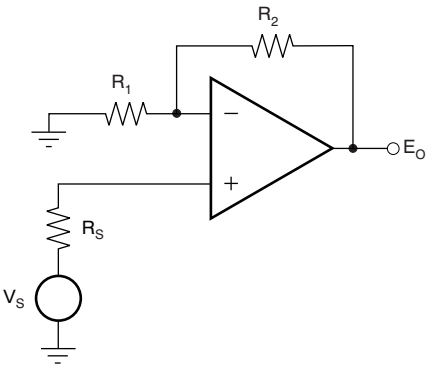
Low-noise circuit design requires careful analysis of all noise sources. External noise sources can dominate in many cases; consider the effect of source resistance on overall op amp noise performance. Total noise of the circuit is the root-sum-square combination of all noise components.

The resistive portion of the source impedance produces thermal noise proportional to the square root of the resistance. This function is plotted in Figure 32. The source impedance is usually fixed; consequently, select the op amp and the feedback resistors to minimize the respective contributions to the total noise.

Figure 33 illustrates both noninverting **(A)** and inverting **(B)** op amp circuit configurations with gain. In circuit configurations with gain, the feedback network resistors also contribute noise. In general, the current noise of the op amp reacts with the feedback resistors to create additional noise components. However, the extremely low current noise of the OPAx141 means that its current noise contribution can be neglected.

The feedback resistor values can generally be chosen to make these noise sources negligible. Note that low impedance feedback resistors load the output of the amplifier. The equations for total noise are shown for both configurations.

A) Noise in Noninverting Gain Configuration



Noise at the output:

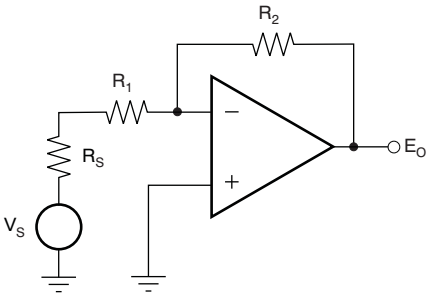
$$E_O^2 = \left(1 + \frac{R_2}{R_1}\right)^2 e_n^2 + \left(\frac{R_2}{R_1}\right)^2 e_1^2 + e_2^2 + \left(1 + \frac{R_2}{R_1}\right)^2 e_s^2$$

Where $e_S = \sqrt{4kTR_S}$ = thermal noise of R_S

$e_1 = \sqrt{4kTR_1}$ = thermal noise of R_1

$e_2 = \sqrt{4kTR_2}$ = thermal noise of R_2

B) Noise in Inverting Gain Configuration



Noise at the output:

$$E_O^2 = \left(1 + \frac{R_2}{R_1 + R_S}\right)^2 e_n^2 + \left(\frac{R_2}{R_1 + R_S}\right)^2 e_1^2 + e_2^2 + \left(\frac{R_2}{R_1 + R_S}\right)^2 e_s^2$$

Where $e_S = \sqrt{4kTR_S}$ = thermal noise of R_S

$e_1 = \sqrt{4kTR_1}$ = thermal noise of R_1

$e_2 = \sqrt{4kTR_2}$ = thermal noise of R_2

For the OPAx141 series of operational amplifiers at 1kHz, $e_n = 6.5nV/\sqrt{Hz}$.

Figure 33. Noise Calculation in Gain Configurations

PHASE-REVERSAL PROTECTION

The OPA141, OPA2141, and OPA4141 family has internal phase-reversal protection. Many FET- and bipolar-input op amps exhibit a phase reversal when the input is driven beyond its linear common-mode range. This condition is most often encountered in noninverting circuits when the input is driven beyond the specified common-mode voltage range, causing the output to reverse into the opposite rail. The input circuitry of the OPA141, OPA2141, and OPA4141 prevents phase reversal with excessive common-mode voltage; instead, the output limits into the appropriate rail (see Figure 22).

OUTPUT CURRENT LIMIT

The output current of the OPAx141 series is limited by internal circuitry to +36mA/–30mA (sourcing/sinking), to protect the device if the output is accidentally shorted. This short-circuit current depends on temperature, as shown in Figure 29.

POWER DISSIPATION AND THERMAL PROTECTION

The OPAx141 series of op amps are capable of driving 2kΩ loads with power-supply voltages of up to ±18V over the specified temperature range. In a single-supply configuration, where the load is connected to the negative supply voltage, the minimum load resistance is 2.8kΩ at a supply voltage of +36V. For lower supply voltages (either single-supply or symmetrical supplies), a lower load resistance may be used, as long as the output current does not exceed 13mA; otherwise, the device short-circuit current protection circuit may activate.

Internal power dissipation increases when operating at high supply voltages. Copper leadframe construction used in the OPA141, OPA2141, and OPA4141 series devices improves heat dissipation compared to conventional materials. Printed circuit board (PCB) layout can also help reduce a possible increase in junction temperature. Wide copper traces help dissipate the heat by acting as an additional heatsink. Temperature rise can be further minimized by soldering the devices directly to the PCB rather than using a socket.

Although the output current is limited by internal protection circuitry, accidental shorting of one or more output channels of a device can result in excessive heating. For instance, when an output is shorted to mid-supply, the typical short-circuit current of 36mA leads to an internal power dissipation of over 600mW at a supply of ±18V.

In the case of a dual OPA2141 in an MSOP-8 package (thermal resistance θ_{JA} = 180°C/W), such power dissipation would lead the die temperature to be 220°C above ambient temperature, when both channels are shorted. This temperature increase significantly decreases the operating life of the device.

In order to prevent excessive heating, the OPAx141 series has an internal thermal shutdown circuit, which shuts down the device if the die temperature exceeds approximately +180°C. Once this thermal shutdown circuit activates, a built-in hysteresis of 15°C ensures that the die temperature must drop to approximately +165°C before the device switches on again.

Additional consideration should be given to the combination of maximum operating voltage, maximum operating temperature, load, and package type. Figure 34 and Figure 35 show several practical considerations when evaluating the OPA2141 (dual version) and the OPA4141 (quad version).

As an example, the OPA4141 has a maximum total quiescent current of 12.4mA (3.1mA/channel) over temperature. The TSSOP-14 package has a typical thermal resistance of 135°C/W. This parameter means that because the junction temperature should not exceed 150°C in order to ensure reliable operation, either the supply voltage must be reduced, or the ambient temperature should remain low enough so that the junction temperature does not exceed 150°C. This condition is illustrated in Figure 34 for various package types. Moreover, resistive loading of the output causes additional power dissipation and thus self-heating, which also must be considered when establishing the maximum supply voltage or operating temperature. To this end, Figure 35 shows the maximum supply voltage versus temperature for a worst-case dc load resistance of 2kΩ.

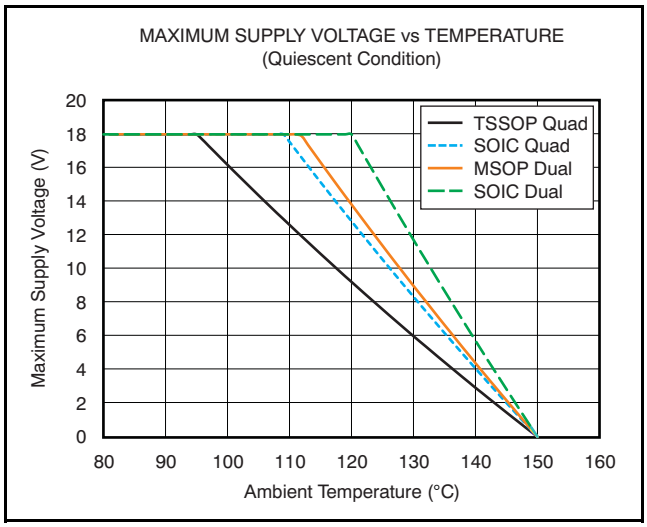


Figure 34. Maximum Supply Voltage vs Temperature (OPA2141 and OPA4141), Quiescent Condition

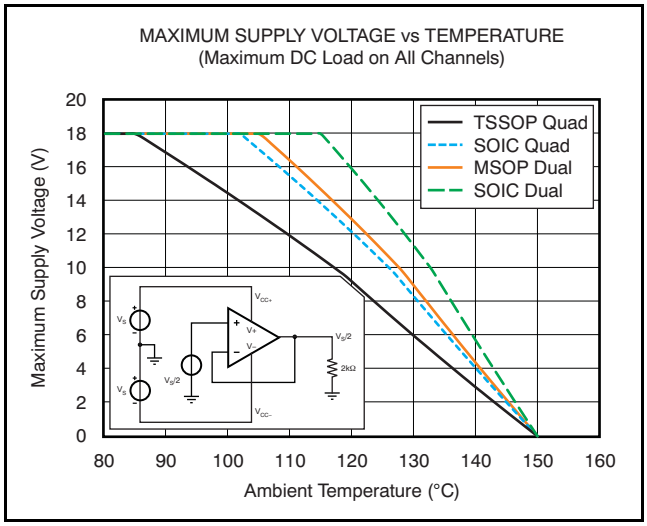


Figure 35. Maximum Supply Voltage vs Temperature (OPA2141 and OPA4141), Maximum DC Load

ELECTRICAL OVERSTRESS

Designers often ask questions about the capability of an operational amplifier to withstand electrical overstress. These questions tend to focus on the device inputs, but may involve the supply voltage pins or even the output pin. Each of these different pin functions have electrical stress limits determined by the voltage breakdown characteristics of the particular semiconductor fabrication process and specific circuits connected to the pin. Additionally, internal electrostatic discharge (ESD) protection is built into these circuits to protect them from accidental ESD events both before and during product assembly.

It is helpful to have a good understanding of this basic ESD circuitry and its relevance to an electrical overstress event. See Figure 36 for an illustration of the ESD circuits contained in the OPAx141 series (indicated by the dashed line area). The ESD protection circuitry involves several current-steering diodes connected from the input and output pins and routed back to the internal power-supply lines, where they meet at an absorption device internal to the operational amplifier. This protection circuitry is intended to remain inactive during normal circuit operation.

An ESD event produces a short duration, high-voltage pulse that is transformed into a short duration, high-current pulse as it discharges through a semiconductor device. The ESD protection circuits are designed to provide a current path around the operational amplifier core to prevent it from being damaged. The energy absorbed by the protection circuitry is then dissipated as heat.

When an ESD voltage develops across two or more of the amplifier device pins, current flows through one or more of the steering diodes. Depending on the path that the current takes, the absorption device may activate. The absorption device has a trigger, or threshold voltage, that is above the normal operating voltage of the OPAx141 but below the device breakdown voltage level. Once this threshold is exceeded, the absorption device quickly activates and clamps the voltage across the supply rails to a safe level.

When the operational amplifier connects into a circuit such as the one Figure 36 shows, the ESD protection components are intended to remain inactive and not become involved in the application circuit operation. However, circumstances may arise where an applied voltage exceeds the operating voltage range of a given pin. Should this condition occur, there is a risk that some of the internal ESD protection circuits may be biased on, and conduct current. Any such current flow occurs through steering diode paths and rarely involves the absorption device.

Figure 36 depicts a specific example where the input voltage, V_{IN}, exceeds the positive supply voltage ($+V_S$) by 500mV or more. Much of what happens in the circuit depends on the supply characteristics. If $+V_S$ can sink the current, one of the upper input steering diodes conducts and directs current to $+V_S$. Excessively high current levels can flow with increasingly higher V_{IN}. As a result, the datasheet specifications recommend that applications limit the input current to 10mA.

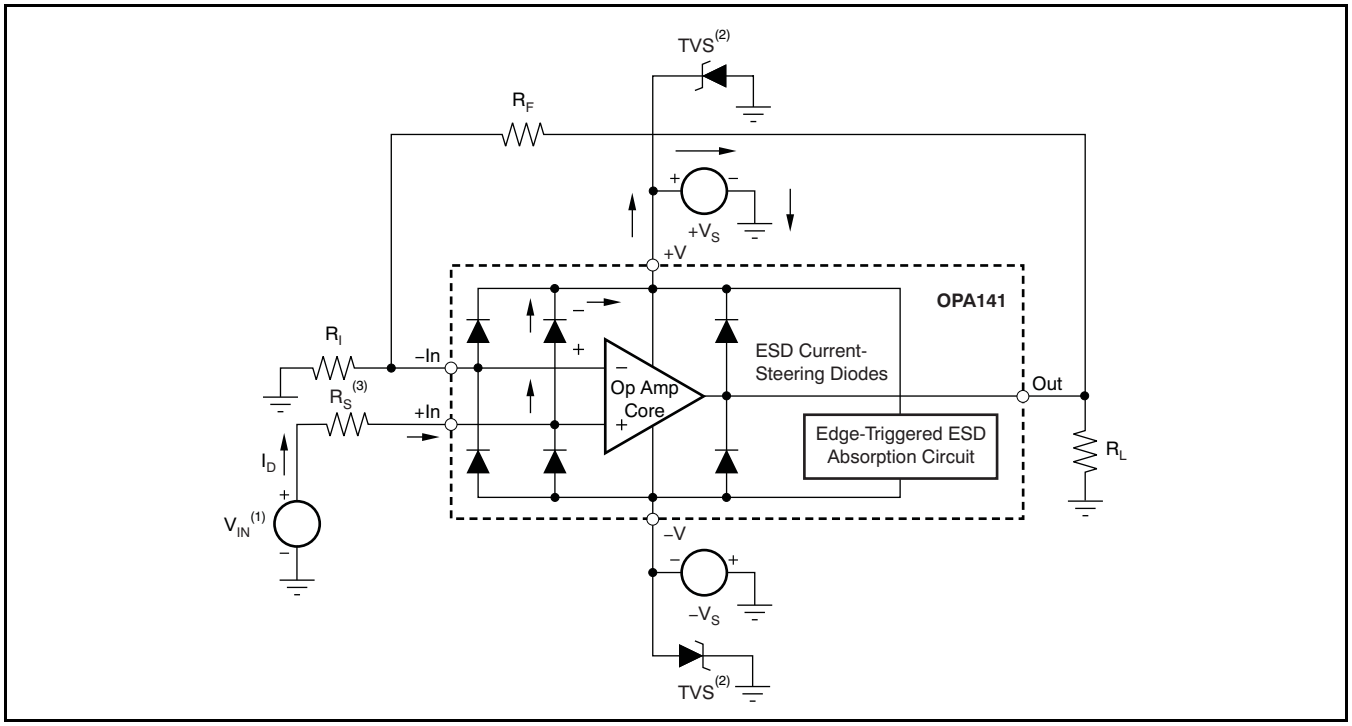
If the supply is not capable of sinking the current, V_{IN} may begin sourcing current to the operational amplifier, and then take over as the source of positive supply voltage. The danger in this case is that the voltage can rise to levels that exceed the operational amplifier absolute maximum ratings.

Another common question involves what happens to the amplifier if an input signal is applied to the input while the power supplies $+V_S$ and/or $-V_S$ are at 0V.

Again, it depends on the supply characteristic while at 0V, or at a level below the input signal amplitude. If the supplies appear as high impedance, then the operational amplifier supply current may be supplied by the input source via the current steering diodes. This state is not a normal bias condition; the amplifier most likely will not operate normally. If the supplies are low impedance, then the current through the steering diodes can become quite high. The current level depends on the ability of the input source to deliver current, and any resistance in the input path.

If there is an uncertainty about the ability of the supply to absorb this current, external zener diodes may be added to the supply pins as shown in Figure 36. The zener voltage must be selected such that the diode does not turn on during normal operation.

However, its zener voltage should be low enough so that the zener diode conducts if the supply pin begins to rise above the safe operating supply voltage level.



(1) $V_{IN} = +V_S + 500mV$.

(2) TVS: $+V_{S(max)} > V_{TVSBR\ (Min)} > +V_S$

(3) Suggested value approximately 1kΩ.

Figure 36. Equivalent Internal ESD Circuitry and Its Relation to a Typical Circuit Application

PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package | Pins	Package qty | Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
OPA141AID	Active	Production	SOIC (D) | 8	75 | TUBE	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	O141A
OPA141AID.B	Active	Production	SOIC (D) | 8	75 | TUBE	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	O141A
OPA141AIDGKR	Active	Production	VSSOP (DGK) | 8	2500 | LARGE T&R	Yes	Call TI | Nipdauag | Nipdau	Level-2-260C-1 YEAR	-40 to 125	141
OPA141AIDGKR.B	Active	Production	VSSOP (DGK) | 8	2500 | LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	141
OPA141AIDGKRG4.B	Active	Production	VSSOP (DGK) | 8	2500 | LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	141
OPA141AIDGKT	Active	Production	VSSOP (DGK) | 8	250 | SMALL T&R	Yes	Call TI | Nipdauag | Nipdau	Level-2-260C-1 YEAR	-40 to 125	141
OPA141AIDGKT.B	Active	Production	VSSOP (DGK) | 8	250 | SMALL T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	141
OPA141AIDR	Active	Production	SOIC (D) | 8	2500 | LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	O141A
OPA141AIDR.B	Active	Production	SOIC (D) | 8	2500 | LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	O141A
OPA141AIDRG4.B	Active	Production	SOIC (D) | 8	2500 | LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	O141A
OPA2141AID	Active	Production	SOIC (D) | 8	75 | TUBE	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	O2141A
OPA2141AID.B	Active	Production	SOIC (D) | 8	75 | TUBE	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	O2141A
OPA2141AIDGKR	Active	Production	VSSOP (DGK) | 8	2500 | LARGE T&R	Yes	Call TI | Nipdauag | Nipdau	Level-2-260C-1 YEAR	-40 to 125	2141
OPA2141AIDGKR.B	Active	Production	VSSOP (DGK) | 8	2500 | LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	2141
OPA2141AIDGKRG4.B	Active	Production	VSSOP (DGK) | 8	2500 | LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	2141
OPA2141AIDGKT	Active	Production	VSSOP (DGK) | 8	250 | SMALL T&R	Yes	Call TI | Nipdauag | Nipdau	Level-2-260C-1 YEAR	-40 to 125	2141
OPA2141AIDGKT.B	Active	Production	VSSOP (DGK) | 8	250 | SMALL T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	2141
OPA2141AIDR	Active	Production	SOIC (D) | 8	2500 | LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	O2141A
OPA2141AIDR.B	Active	Production	SOIC (D) | 8	2500 | LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	O2141A
OPA4141AID	Active	Production	SOIC (D) | 14	50 | TUBE	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	O4141A
OPA4141AID.B	Active	Production	SOIC (D) | 14	50 | TUBE	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	O4141A
OPA4141AIDG4.B	Active	Production	SOIC (D) | 14	50 | TUBE	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	O4141A
OPA4141AIDR	Active	Production	SOIC (D) | 14	2500 | LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	O4141A
OPA4141AIDR.B	Active	Production	SOIC (D) | 14	2500 | LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	O4141A
OPA4141AIPW	Active	Production	TSSOP (PW) | 14	90 | TUBE	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	O4141A
OPA4141AIPW.B	Active	Production	TSSOP (PW) | 14	90 | TUBE	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	O4141A

Orderable part number	Status (1)	Material type (2)	Package | Pins	Package qty | Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
OPA4141AIPWG4.B	Active	Production	TSSOP (PW) | 14	90 | TUBE	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	O4141A
OPA4141AIPWR	Active	Production	TSSOP (PW) | 14	2000 | LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	O4141A
OPA4141AIPWR.B	Active	Production	TSSOP (PW) | 14	2000 | LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	O4141A

(1) **Status:** For more details on status, see our product life cycle.

(2) **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

(3) **RoHS values:** Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

(4) **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

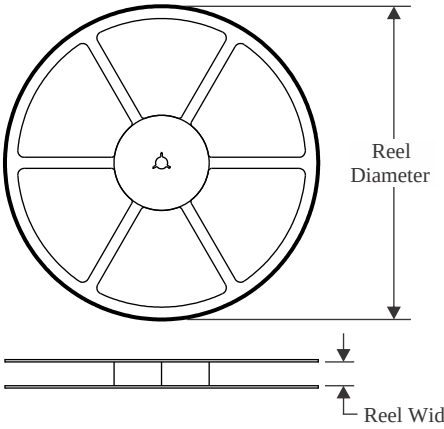
(5) **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

(6) **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

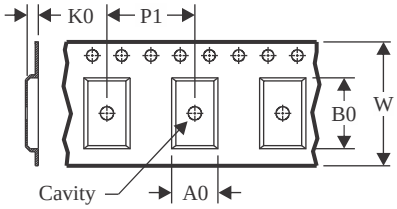
Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

TAPE AND REEL INFORMATION

REEL DIMENSIONS

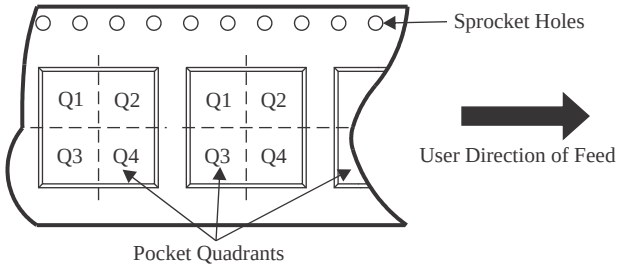


TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

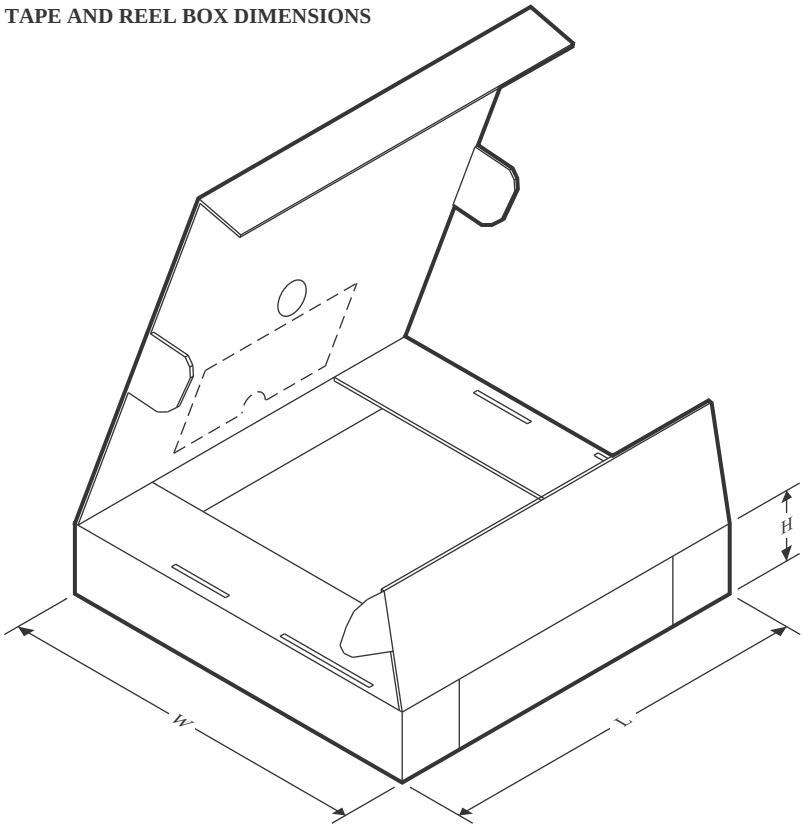
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
OPA141AIDGKR	VSSOP	DGK	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
OPA141AIDGKT	VSSOP	DGK	8	250	180.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
OPA141AIDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
OPA2141AIDGKR	VSSOP	DGK	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
OPA2141AIDGKT	VSSOP	DGK	8	250	180.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
OPA2141AIDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
OPA4141AIDR	SOIC	D	14	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
OPA4141AIPWR	TSSOP	PW	14	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1

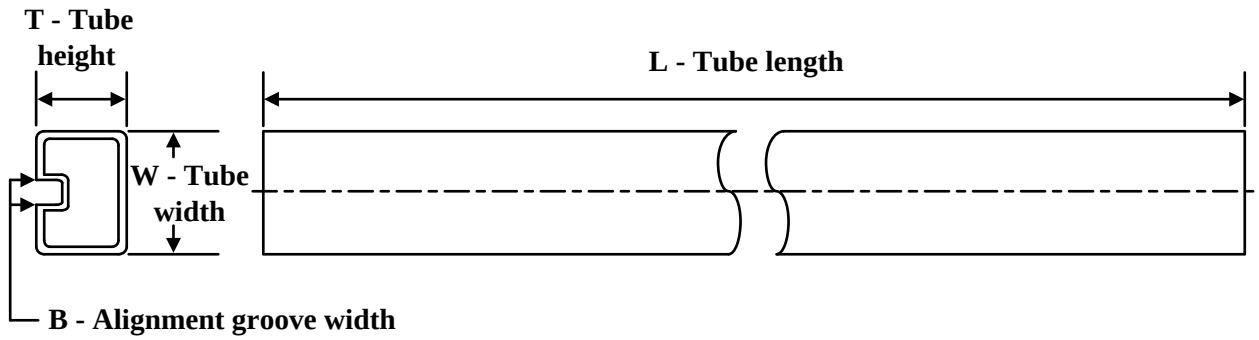
TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
OPA141AIDGKR	VSSOP	DGK	8	2500	356.0	356.0	35.0
OPA141AIDGKT	VSSOP	DGK	8	250	210.0	185.0	35.0
OPA141AIDR	SOIC	D	8	2500	356.0	356.0	35.0
OPA2141AIDGKR	VSSOP	DGK	8	2500	353.0	353.0	32.0
OPA2141AIDGKT	VSSOP	DGK	8	250	210.0	185.0	35.0
OPA2141AIDR	SOIC	D	8	2500	356.0	356.0	35.0
OPA4141AIDR	SOIC	D	14	2500	356.0	356.0	35.0
OPA4141AIPWR	TSSOP	PW	14	2000	356.0	356.0	35.0

TUBE



*All dimensions are nominal

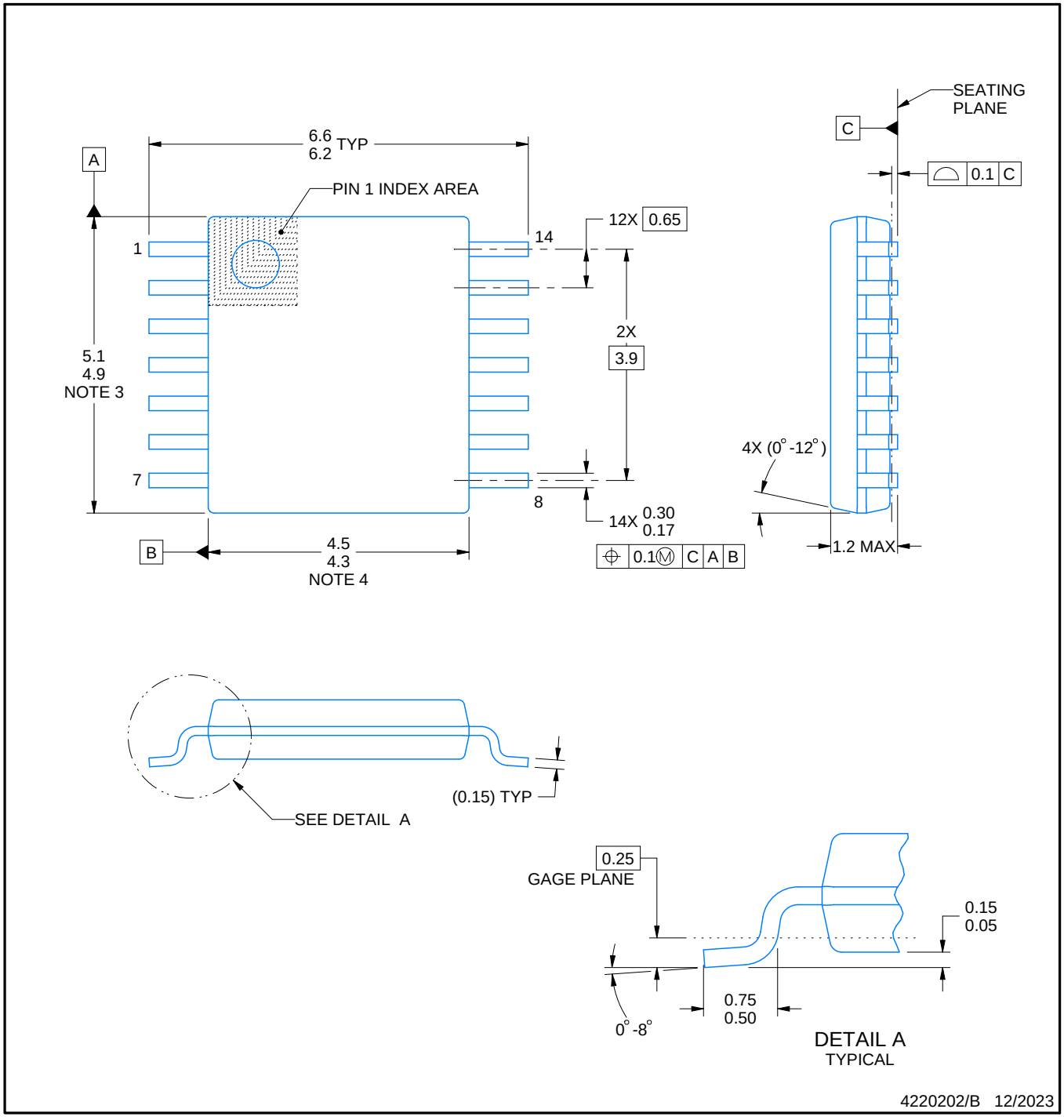
Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
OPA141AID	D	SOIC	8	75	506.6	8	3940	4.32
OPA141AID.B	D	SOIC	8	75	506.6	8	3940	4.32
OPA2141AID	D	SOIC	8	75	506.6	8	3940	4.32
OPA2141AID.B	D	SOIC	8	75	506.6	8	3940	4.32
OPA4141AID	D	SOIC	14	50	506.6	8	3940	4.32
OPA4141AID.B	D	SOIC	14	50	506.6	8	3940	4.32
OPA4141AIDG4.B	D	SOIC	14	50	506.6	8	3940	4.32
OPA4141AIPW	PW	TSSOP	14	90	508	8.5	3250	2.8
OPA4141AIPW.B	PW	TSSOP	14	90	508	8.5	3250	2.8
OPA4141AIPWG4.B	PW	TSSOP	14	90	508	8.5	3250	2.8

PACKAGE OUTLINE

PW0014A

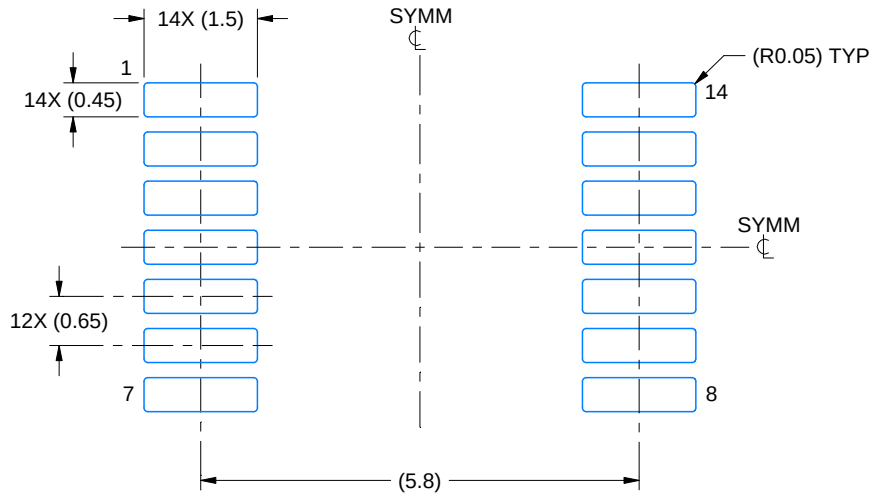
TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE

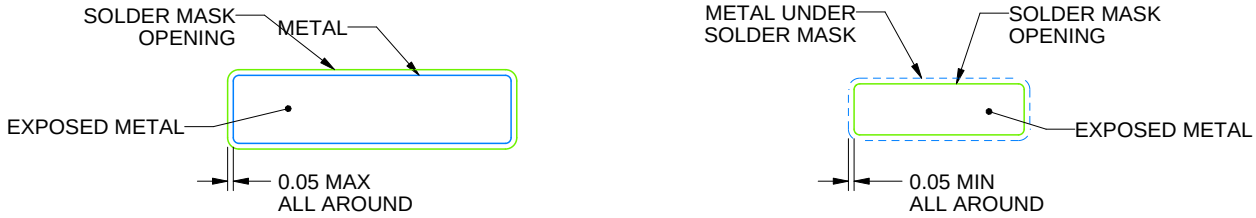


NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
5. Reference JEDEC registration MO-153.



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE: 10X

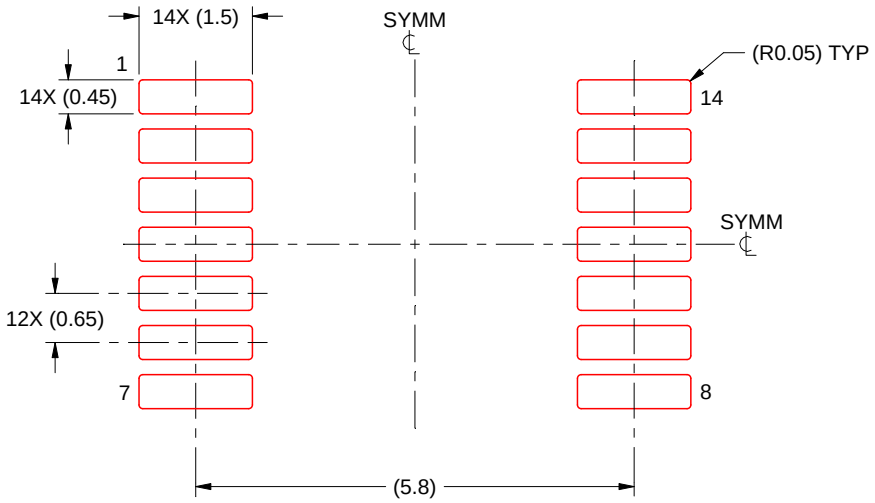


SOLDER MASK DETAILS

4220202/B 12/2023

NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

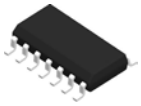


SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL
SCALE: 10X

4220202/B 12/2023

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

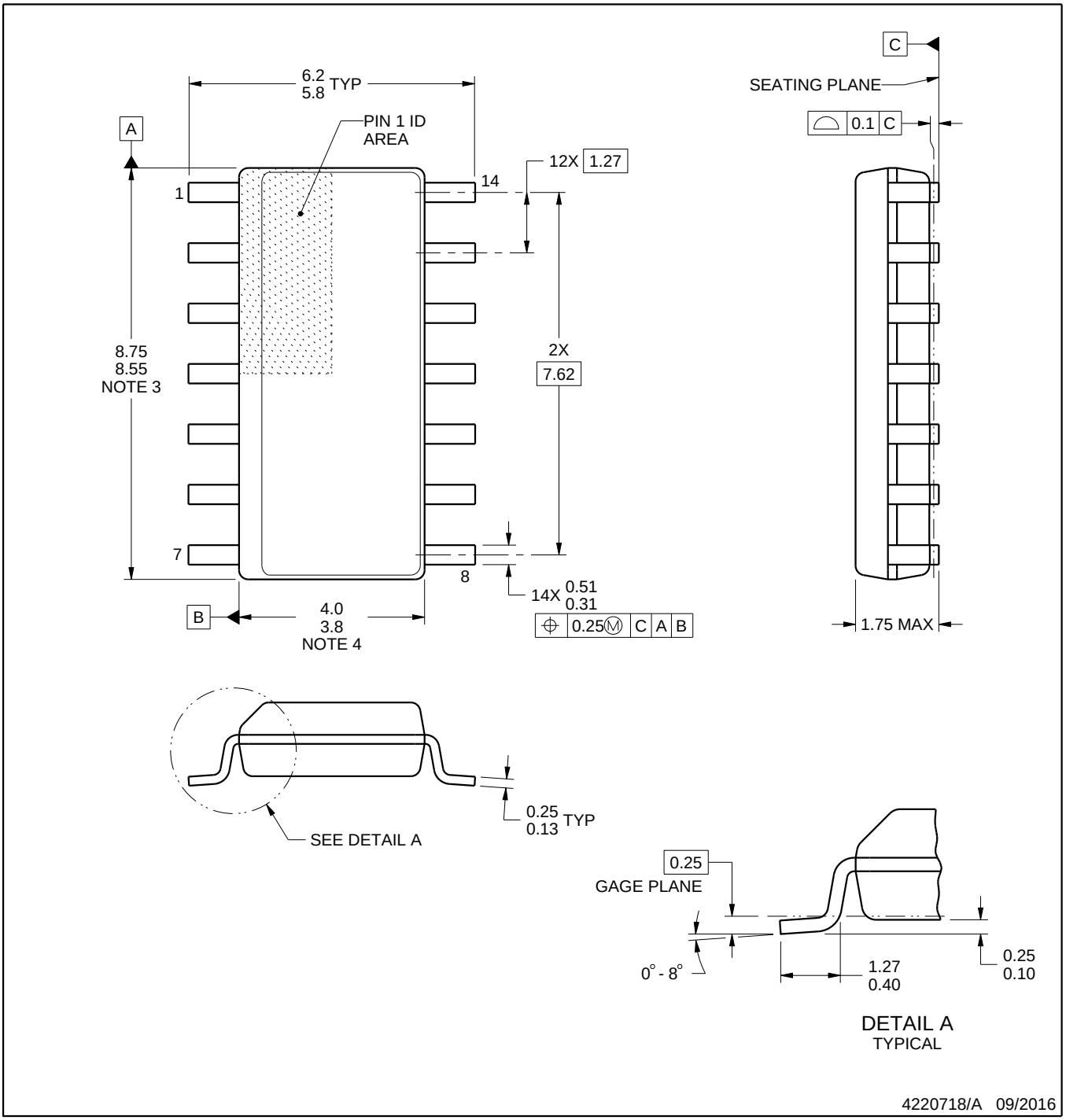


PACKAGE OUTLINE

D0014A

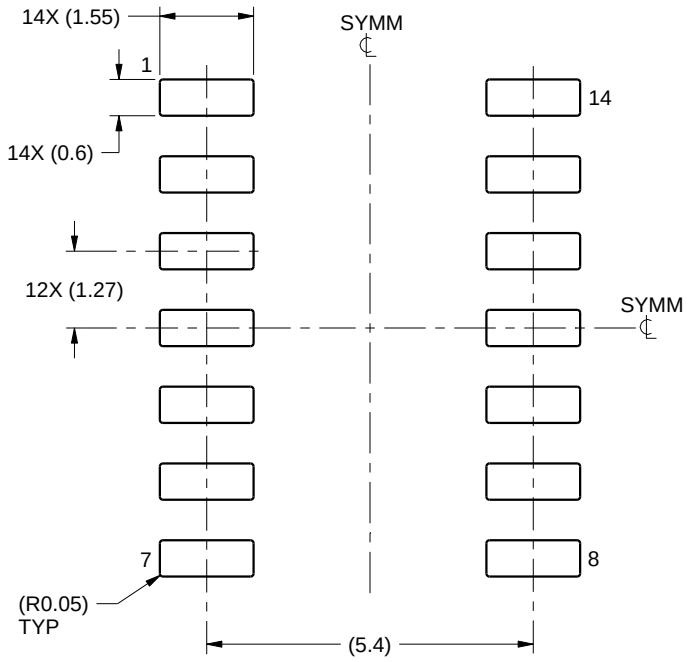
SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT

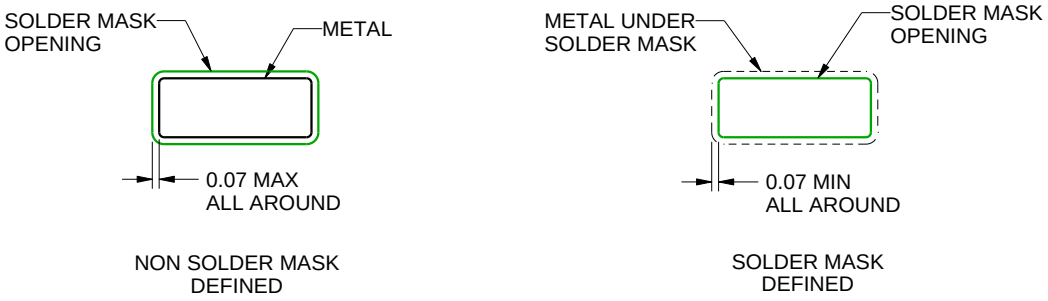


NOTES:

1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm, per side.
4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm, per side.
5. Reference JEDEC registration MS-012, variation AB.



LAND PATTERN EXAMPLE
SCALE:8X



SOLDER MASK DETAILS

4220718/A 09/2016

NOTES: (continued)

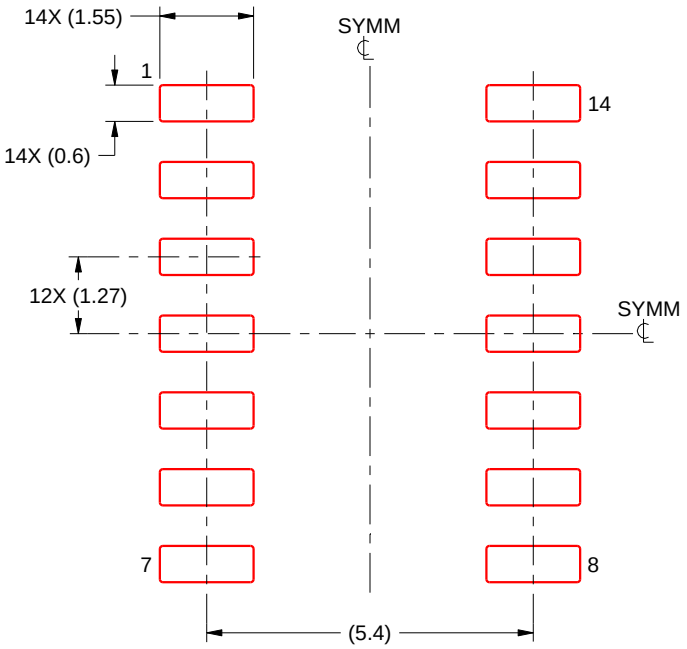
6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

EXAMPLE STENCIL DESIGN

D0014A

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT

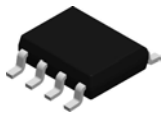


SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL
SCALE:8X

4220718/A 09/2016

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

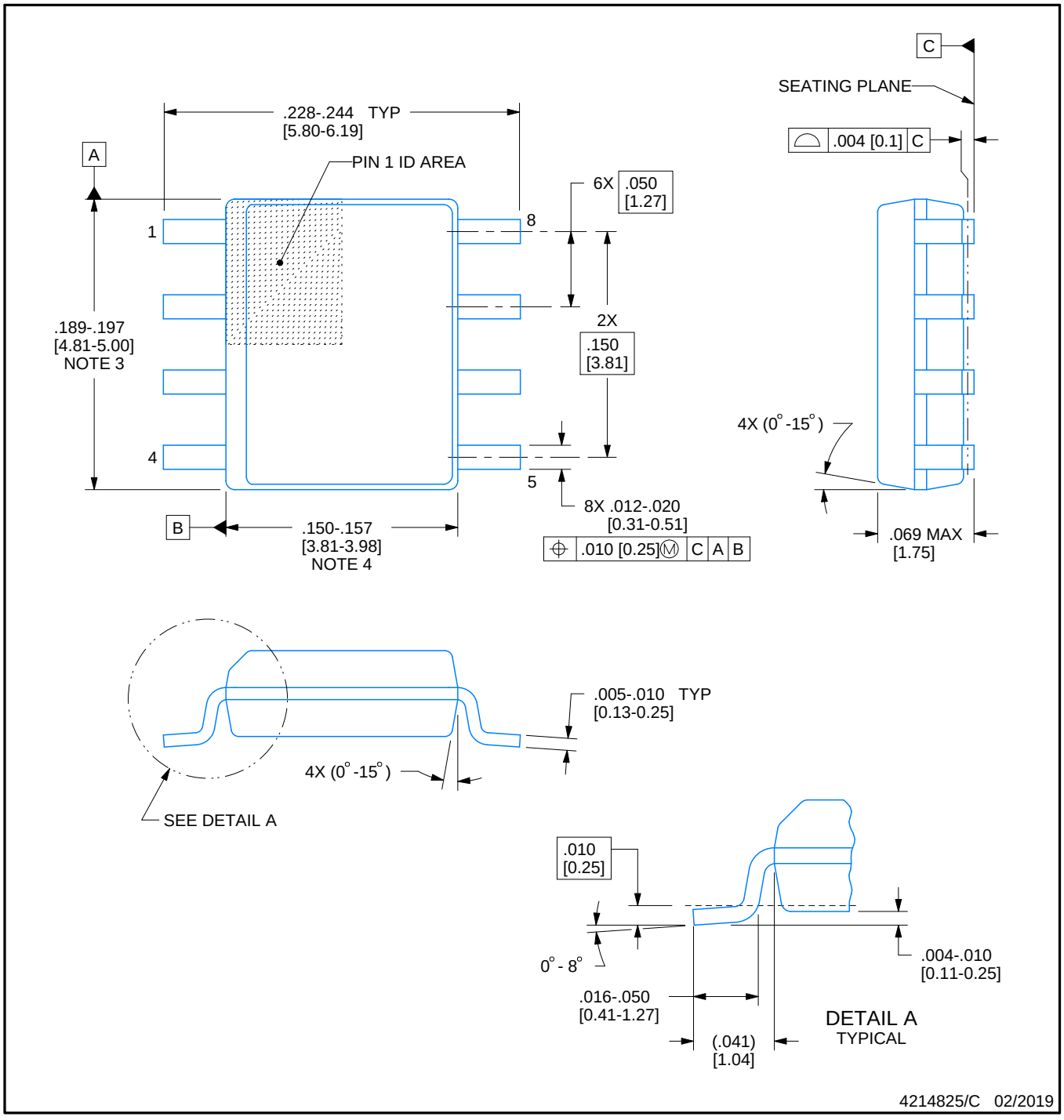


PACKAGE OUTLINE

D0008A

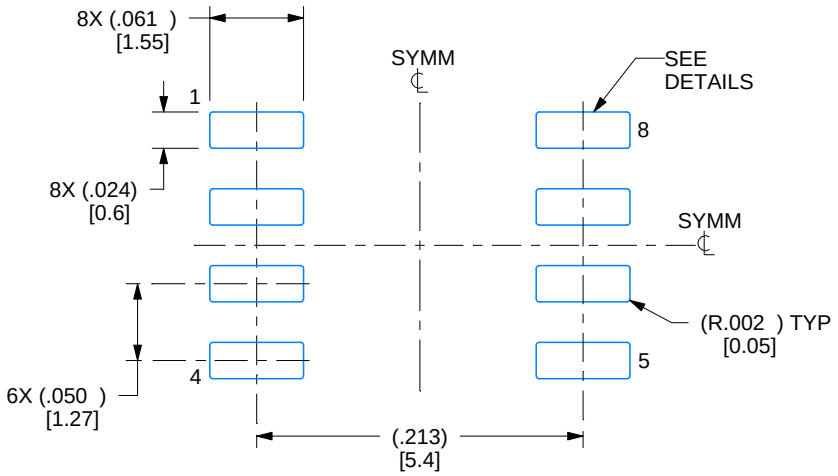
SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT

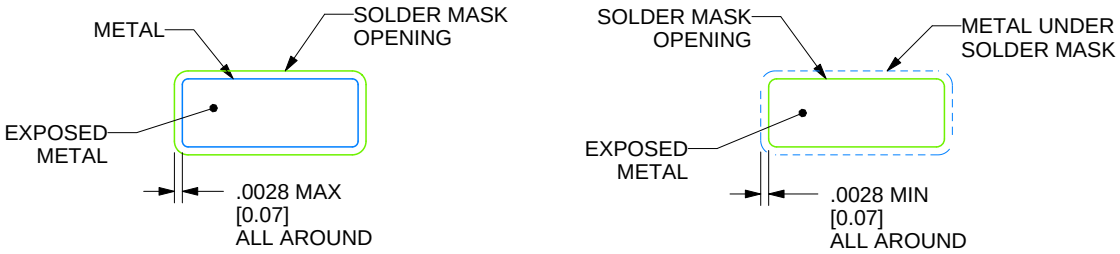


NOTES:

1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
4. This dimension does not include interlead flash.
5. Reference JEDEC registration MS-012, variation AA.



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE:8X



SOLDER MASK DETAILS

4214825/C 02/2019

NOTES: (continued)

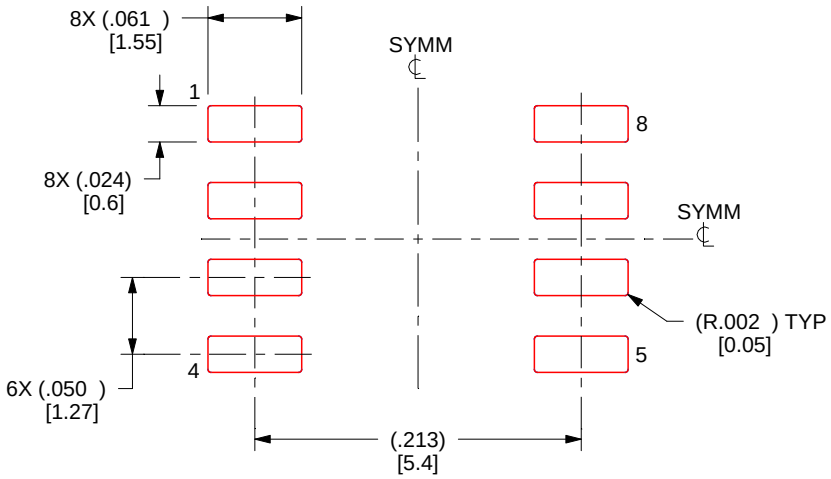
6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

EXAMPLE STENCIL DESIGN

D0008A

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



SOLDER PASTE EXAMPLE
BASED ON .005 INCH [0.125 MM] THICK STENCIL
SCALE:8X

4214825/C 02/2019

NOTES: (continued)

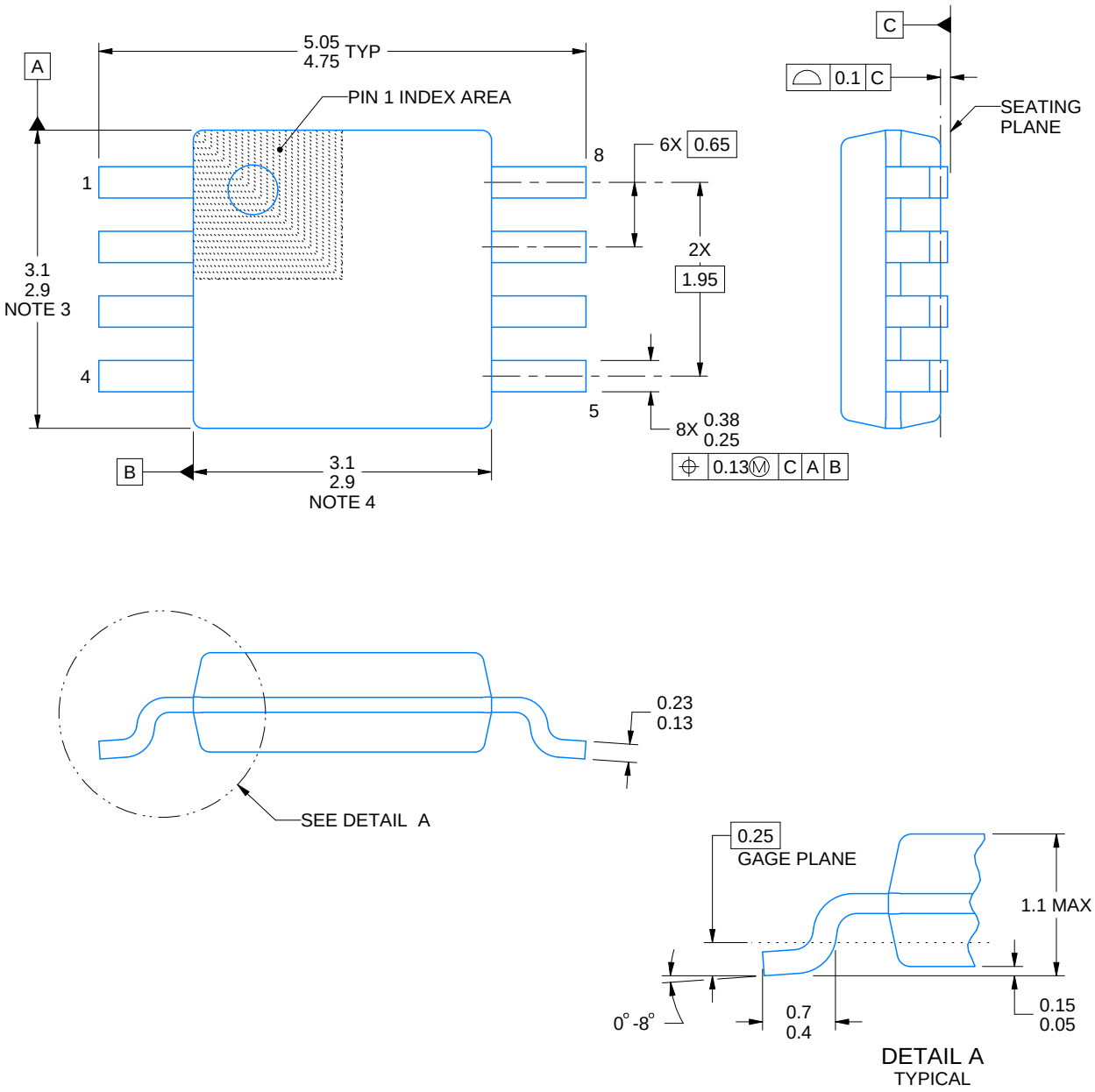
8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

PACKAGE OUTLINE

DGK0008A

VSSOP - 1.1 mm max height

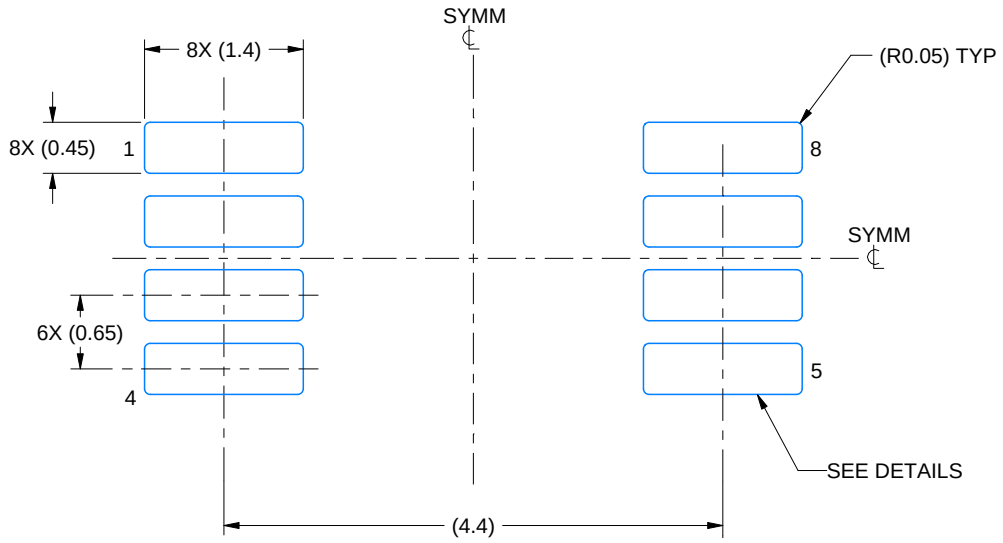
SMALL OUTLINE PACKAGE



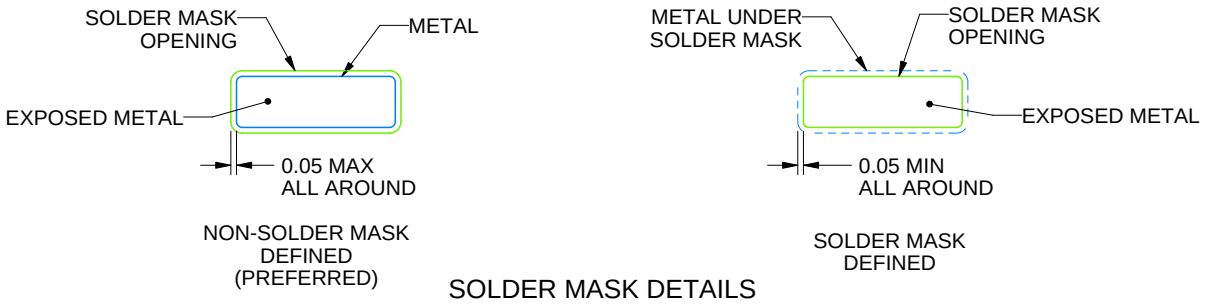
PowerPAD is a trademark of Texas Instruments.

NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
5. Reference JEDEC registration MO-187.



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE: 15X

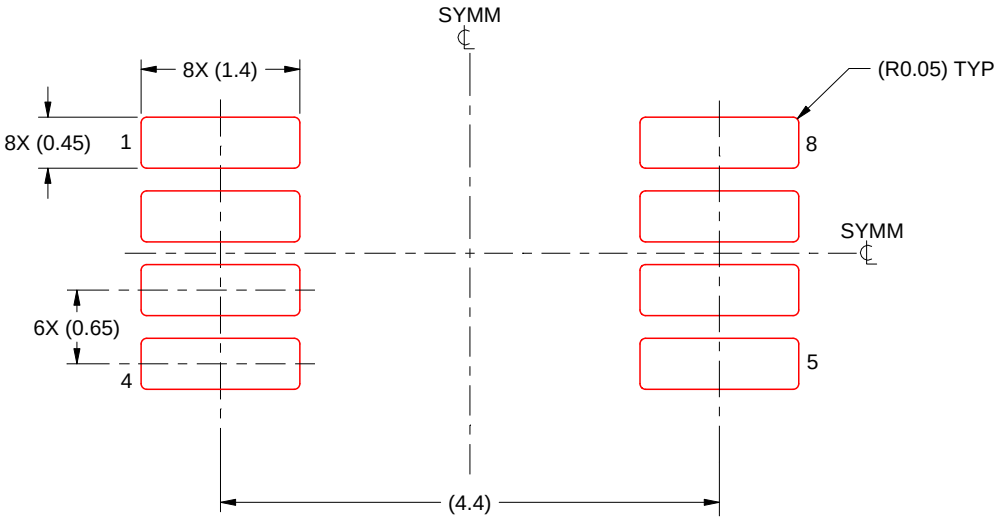


SOLDER MASK DETAILS

4214862/A 04/2023

NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.
8. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.
9. Size of metal pad may vary due to creepage requirement.



SOLDER PASTE EXAMPLE
SCALE: 15X

4214862/A 04/2023

NOTES: (continued)

11. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
12. Board assembly site may have different recommendations for stencil design.

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